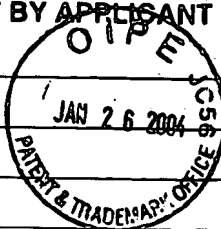


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| Examiner Unknown | | Filing Date October 9, 2003 | Group Unknown |



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V. J. Foster

Date Considered

04/29/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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V. The War

Date Considered 04/29/05

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